



**SMD Power Inductor**

**TMPC1206HP-Series(MG)-D**

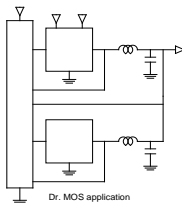
**1. Features**

1. Carbonyl Powder.
2. Compact design.
3. High current · low DCR · high efficiency.
4. Very low acoustic noise and very low leakage flux noise.
5. High reliability.
6. 100% Lead(Pb)-Free and RoHS compliant.

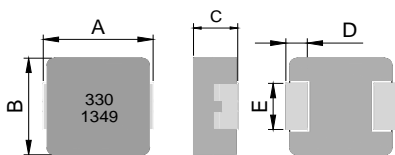


**2. Applications**

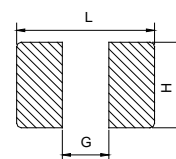
Note PC power system · incl. IMVP-6  
DC/DC converter .



**3. Dimensions**



**Recommend PC Board Pattern**



Series	A(mm)	B(mm)	C(mm)	D(mm)	E(mm)
TMPC1206HP	13.5±0.5	12.5±0.3	5.7±0.3	2.3±0.3	4.7±0.3

L(mm)	G(mm)	H(mm)
14.2	8.0	5.0

**4. Part Numbering**



- A: Series
- B: Dimension
- C: Type
- D: Inductance
- E: Inductance Tolerance
- F: 印 D/C
- BxC
- HP:H:Carbonyl Powder,P:PAD broaden.
- 330=33uH
- M=±20%,Y=±30%
- 印字:黑色,330 及 D/C 1349 (13 年,49 週期,依實際生產周期而定)

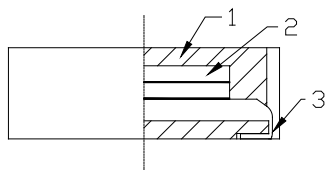
## 5. Specification

Part Number	Inductance L0 (uH)±20% @ 0 A	I rms (A) Typ.	I sat 1 (A) Typ.	I sat 2 (A) Typ.	DCR (mΩ) Typ. @25°C	DCR (mΩ) Max. @25°C
TMPC1206HP-1R5MG-D	1.50	26	43	50	2.7	3.2
TMPC1206HP-2R2MG-D	2.20	21	34	43	4.0	4.7
TMPC1206HP-3R3MG-D	3.30	17	28	35	5.8	7.1
TMPC1206HP-4R7MG-D	4.70	16	25	30	9.5	11.5
TMPC1206HP-5R6MG-D	5.60	15.5	22	28	10.8	12.6
TMPC1206HP-6R8MG-D	6.80	15	19	25	12	13.8
TMPC1206HP-100MG-D	10.0	11	15.5	21	18	20.7
TMPC1206HP-120MG-D	12.0	9.5	13.5	18	20	23
TMPC1206HP-150MG-D	15.0	9.0	13	16	25	29
TMPC1206HP-180MG-D	18.0	8.5	12	15	30	35
TMPC1206HP-220MG-D	22.0	8.0	11	14	34	39.5
TMPC1206HP-270MG-D	27.0	7.0	9.0	13	49	56
TMPC1206HP-330MG-D	33.0	6.0	8.0	12.0	65	75
TMPC1206HP-470MG-D	47.0	5.5	7.0	11.0	80	90
TMPC1206HP-560MG-D	56.0	5.3	6.5	10	101	118
TMPC1206HP-680MG-D	68.0	5.0	6.0	9.0	120	140
TMPC1206HP-820MG-D	82.0	4.5	5.5	8.5	138	161
TMPC1206HP-101MG-D	100	4.0	5.0	8.0	180	200
TMPC1206HP-121MG-D	120	3.5	4.5	7.0	210	235
TMPC1206HP-151MG-D	150	3.0	4.0	6.0	300	350

Note:

1. Test frequency : L : 100KHz /1.0V;
2. All test data referenced to 25°C ambient.
3. Testing Instrument : L/Q: HP4284A,CH11025,CH3302,CH1320 ,CH1320S LCR METER / Rdc:CH16502,Agilent33420A MICRO OHMMETER.
4. Heat Rated Current (I rms) will cause the coil temperature rise approximately  $\Delta t$  of 40°C (keep 1min.).
5. Saturation Current (I sat 1) will cause L0 to drop 20% typical. (keep quickly).
6. Saturation Current (I sat 2) will cause L0 to drop 30% typical. (keep quickly)
7. The part temperature (ambient + temp rise) should not exceed 125°C under worst case operating conditions. Circuit design, component, PCB trace size and thickness, airflow and other cooling provisions all affect the part temperature. Part temperature should be verified in the end application.
8. Special inquiries besides the above common used types can be met on your requirement.

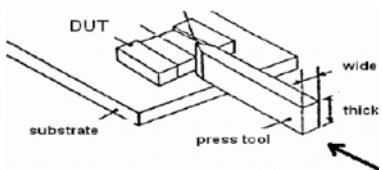
### 6. Material List



NO	Items	Materials
1	Core	Carbonyl Powder.
2	Wire	Polyester Wire or equivalent.
3	Solder Plating	100% Pb free solder

### 7. Reliability and Test Condition

Item	Performance	Test Condition															
Operating temperature	-40~+125°C																
Storage temperature	-40~+125°C (on board)																
<b>Electrical Performance Test</b>																	
Inductance	Refer to standard electrical characteristics list.	HP4284A, CH11025, CH3302, CH1320, CH1320S LCR Meter.															
DCR		CH16502, Agilent33420A Micro-Ohm Meter.															
Saturation Current (Isat)	$\Delta L \leq 20\%$ typical.	Saturation DC Current (Isat) will cause L0 to drop $\Delta L(\%)$ (keep quickly).															
Heat Rated Current (Irms)	Approximately $\Delta T \leq 40^\circ\text{C}$	Heat Rated Current (Irms) will cause the coil temperature rise $\Delta T(^\circ\text{C})$ without core loss. 1. Applied the allowed DC current(keep 1 min.). 2. Temperature measured by digital surface thermometer															
<b>Reliability Test</b>																	
Life Test	Appearance : No damage. Inductance : within $\pm 10\%$ of initial value Q : Shall not exceed the specification value. RDC : within $\pm 15\%$ of initial value and shall not exceed the specification value	Preconditioning: Run through IR reflow for 2 times.( IPC/JEDEC J-STD-020D Classification Reflow Profiles) Temperature : 125 $\pm 2^\circ\text{C}$ (Bead) Temperature : 85 $\pm 2^\circ\text{C}$ (Inductor) Applied current : rated current Duration : 1000 $\pm 12$ hrs Measured at room temperature after placing for 24 $\pm 2$ hrs															
Load Humidity		Preconditioning: Run through IR reflow for 2 times.( IPC/JEDEC J-STD-020D Classification Reflow Profiles) Humidity : 85 $\pm 2\%$ R.H., Temperature : 85 $\pm 2^\circ\text{C}$ Duration : 1000hrs Min. with 100% rated current Measured at room temperature after placing for 24 $\pm 2$ hrs															
Thermal shock		Preconditioning: Run through IR reflow for 2 times.( IPC/JEDEC J-STD-020D Classification Reflow Profiles) Condition for 1 cycle Step1 : -40 $\pm 2^\circ\text{C}$ 30 $\pm 5$ min Step2 : 25 $\pm 2^\circ\text{C}$ $\leq 0.5$ min Step3 : 105 $\pm 2^\circ\text{C}$ 30 $\pm 5$ min Number of cycles : 500 Measured at room temperature after placing for 24 $\pm 2$ hrs															
Vibration		Oscillation Frequency: 10 ~ 2K ~ 10Hz for 20 minutes Equipment : Vibration checker Total Amplitude: 1.52mm $\pm 10\%$ Testing Time : 12 hours(20 minutes, 12 cycles each of 3 orientations).															
Shock		<table border="1"> <thead> <tr> <th>Type</th> <th>Peak value (g's)</th> <th>Normal duration (D) (ms)</th> <th>Wave form</th> <th>Velocity change (Vi)ft/sec</th> </tr> </thead> <tbody> <tr> <td>SMD</td> <td>1500</td> <td>0.5</td> <td>Half-sine</td> <td>15.4</td> </tr> <tr> <td>Lead</td> <td>100</td> <td>6</td> <td>Half-sine</td> <td>12.3</td> </tr> </tbody> </table>	Type	Peak value (g's)	Normal duration (D) (ms)	Wave form	Velocity change (Vi)ft/sec	SMD	1500	0.5	Half-sine	15.4	Lead	100	6	Half-sine	12.3
Type		Peak value (g's)	Normal duration (D) (ms)	Wave form	Velocity change (Vi)ft/sec												
SMD	1500	0.5	Half-sine	15.4													
Lead	100	6	Half-sine	12.3													
Bending	Shall be mounted on a FR4 substrate of the following dimensions: $\geq 0805: 40 \times 100 \times 1.2\text{mm}$ $< 0805: 40 \times 100 \times 0.8\text{mm}$ Bending depth: $\geq 0805: 1.2\text{mm}$ $< 0805: 0.8\text{mm}$ duration of 10 sec.																

Item	Performance	Test Method and Remarks						
Soderability	More than 95% of the terminal electrode should be covered with solder.	Preheat: 150°C, 60sec. Solder: Sn99.5%-Cu0.5%. Temperature: 245±5°C. Flux for lead free: Rosin. 9.5%. Dip time: 4±1sec. Depth: completely cover the termination						
Resistance to Soldering Heat		Number of heat cycles: 1 <table border="1"> <tr> <th>Temperature (°C)</th> <th>Time(s)</th> <th>Temperature ramp/immersion and emersion rate</th> </tr> <tr> <td>260 ±5(solder temp)</td> <td>10 ±1</td> <td>25mm/s ±6 mm/s</td> </tr> </table>	Temperature (°C)	Time(s)	Temperature ramp/immersion and emersion rate	260 ±5(solder temp)	10 ±1	25mm/s ±6 mm/s
Temperature (°C)	Time(s)	Temperature ramp/immersion and emersion rate						
260 ±5(solder temp)	10 ±1	25mm/s ±6 mm/s						
Terminal Strength	Appearance : No damage. Inductance : within±10% of initial value Q : Shall not exceed the specification value. RDC : within ±15% of initial value and shall not exceed the specification value	Preconditioning: Run through IR reflow for 2 times.( IPC/JEDEC J-STD-020DClassification Reflow Profiles With the component mounted on a PCB with the device to be tested, apply a force (>0805:1kg , <=0805:0.5kg)to the side of a device being tested. This force shall be applied for 60 +1 seconds. Also the force shall be applied gradually as not to apply a shock to the component being tested. 						

## 8. Soldering and Mounting

### (1) Soldering

Mildly activated rosin fluxes are preferred. The minimum amount of solder can lead to damage from the stresses caused by the difference in coefficients of expansion between solder, chip and substrate. TAI-TECH terminations are suitable for re-flow soldering systems. If hand soldering cannot be avoided, the preferred technique is the utilization of hot air soldering tools.

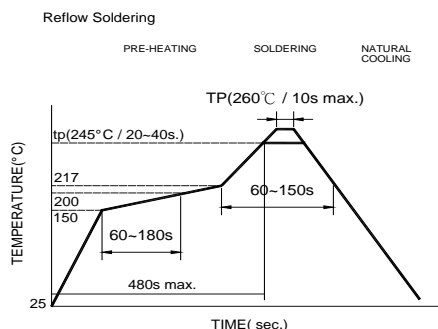
### (2) Solder re-flow:

Recommended temperature profiles for re-flow soldering in Figure 1.

### (3) Soldering Iron:

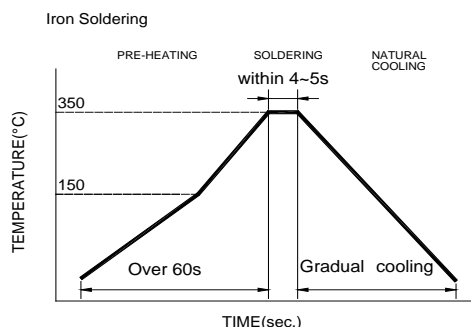
Products attachment with a soldering iron is discouraged due to the inherent process control limitations. In the event that a soldering iron must be employed the following precautions are recommended.

- Preheat circuit and products to 150°C
- Never contact the ceramic with the i
- 355°C tip temperature (max)
- 1.0mm tip diameter (max)



Reflow times: 3 times max.

Fig.1

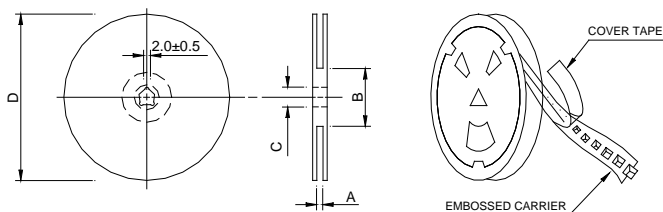


Iron Soldering times: 1 times max.

Fig.2

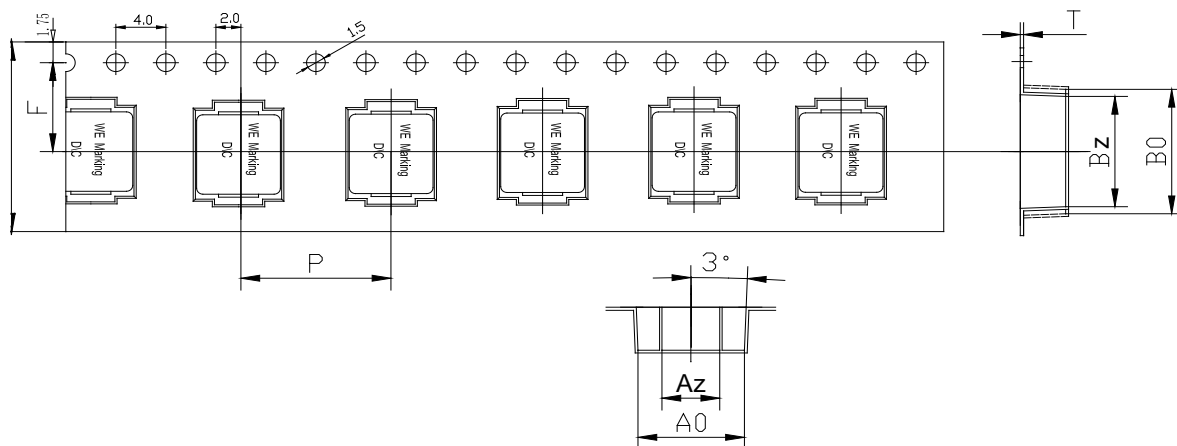
### 9. Packaging Information

#### (1) Reel Dimension



Type	A(mm)	B(mm)	C(mm)	D(mm)
13"x24mm	24.0±0.5	100±2	13.5±0.5	330

#### (2) Tape Dimension

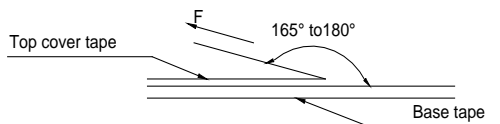


Series	Size	Bo(mm)	Bz(mm)	Ao(mm)	Az(mm)	Ko(mm)	P(mm)	W(mm)	F(mm)	t(mm)
TMPC	1206	14.2±0.1	13.0±0.1	13.0±0.1	7.0±0.1	6.5±0.1	16.0±0.1	24±0.3	11.5±0.1	0.35±0.05

#### (3) Packaging Quantity

TMPC	1206
Chip / Reel	500
Inner box	1000
Carton	4000

#### (4) Tearing Off Force



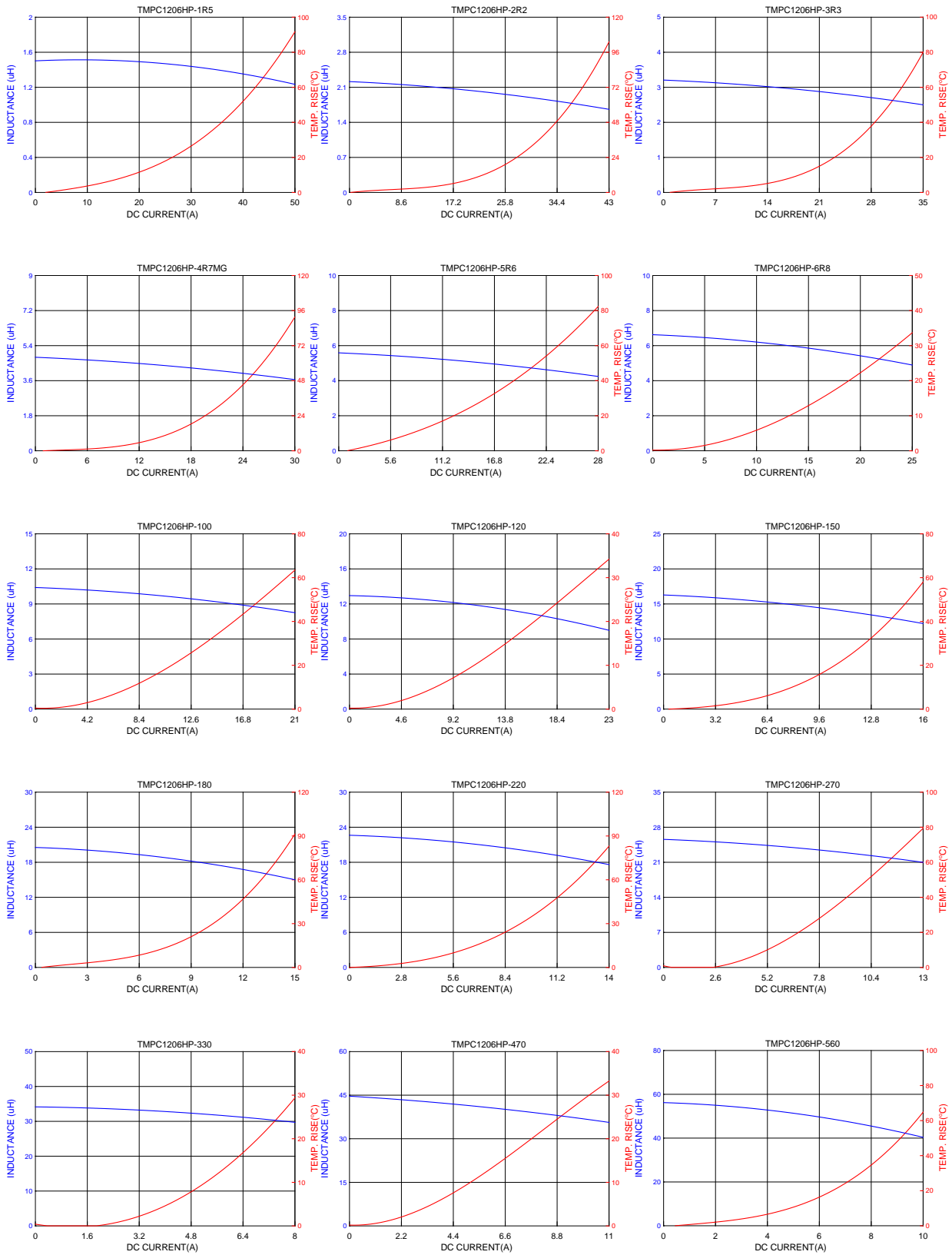
The force for tearing off cover tape is 10 to 130 grams in the arrow direction under the following conditions(referenced ANSI/EIA-481-C-2003 of 4.11 stadnard).

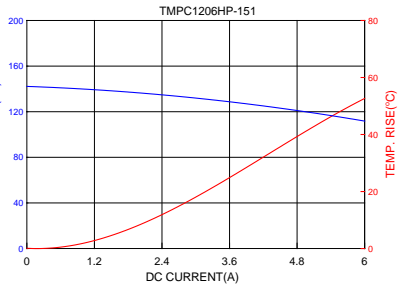
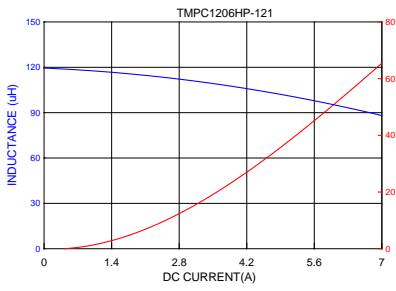
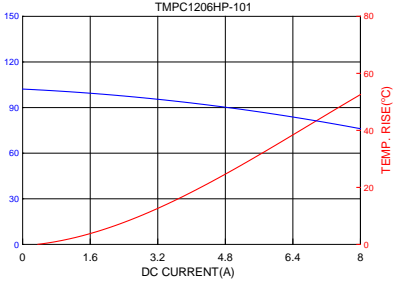
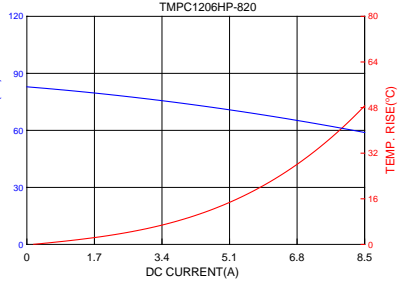
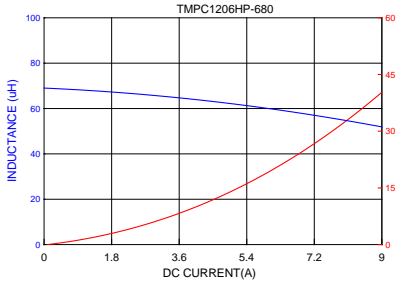
Room Temp. ( °C)	Room Humidity (%)	Room atm (hPa)	Tearing Speed mm/min
5~35	45~85	860~1060	300

#### Application Notice

- Storage Conditions (component level)  
To maintain the solderability of terminal electrodes:
  1. TAI-TECH products meet IPC/JEDEC J-STD-020D standard-MSL, level 1.
  2. Temperature and humidity conditions: Less than 40°C and 60% RH.
  3. Recommended products should be used within 12 months form the time of delivery.
  4. The packaging material should be kept where no chlorine or sulfur exists in the air.
- Transportation
  1. Products should be handled with care to avoid damage or contamination from perspiration and skin oils.
  2. The use of tweezers or vacuum pick up is strongly recommended for individual components.
  3. Bulk handling should ensure that abrasion and mechanical shock are minimized.

### 10. Typical Performance Curves










簽名有效  
For Question  
Please Contact with SGS  
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# 測試報告

## Test Report

號碼(No.) : CE/2014/14393 日期(Date) : 2014/01/24 頁數(Page) : 1 of 13

西北臺慶科技股份有限公司 / TAI-TECH ADVANCED ELECTRONICS CO., LTD. 

(東莞臺慶精密電子有限公司 / TAI-TECH ADVANCED ELECTRONICS (DONGGUAN) CO. LTD.)

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(江蘇省昆山市蓬朗昆嘉高科技工業區郭澤路 / GUO-ZE ROAD, KUNJIA HI-TECH INDUSTRIAL PARK, KUN-SHAN, JIANG-SU, CHINA)

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以下測試樣品係由申請廠商所提供及確認 (The following sample(s) was/were submitted and identified by/on behalf of the applicant as) :

樣品名稱(Sample Description) : SMD POWER INDUCTOR

樣品型號(Style/Item No.) : TMPB, TMPC, SLPI, SMPI, SMPI-P3, EPI(ePI), VMPI, MLPI SERIES

收件日期(Sample Receiving Date) : 2014/01/20

測試期間(Testing Period) : 2014/01/20 TO 2014/01/24

=====

測試結果(Test Results) : 請見下一頁 (Please refer to next pages).

  
Troy Chang, Manager Tech  
Signed for and on behalf of  
SGS TAIWAN LTD  
Chemical Laboratory - Taipei

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## Test Report

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### 測試結果(Test Results)

測試部位(PART NAME)No.1 : 整體混測 (MIXED ALL PARTS)

測試項目 (Test Items)	單位 (Unit)	測試方法 (Method)	方法偵測 極限值 (MDL)	結果 (Result)
				No.1
鎘 / Cadmium (Cd)	mg/kg	參考IEC 62321-5: 2013方法, 以感應耦合電漿原子發射光譜儀檢測. / With reference to IEC 62321-5: 2013 and performed by ICP-AES.	2	n.d.
鉛 / Lead (Pb)	mg/kg	參考IEC 62321-5: 2013方法, 以感應耦合電漿原子發射光譜儀檢測. / With reference to IEC 62321-5: 2013 and performed by ICP-AES.	2	n.d.
汞 / Mercury (Hg)	mg/kg	參考IEC 62321-4: 2013方法, 以感應耦合電漿原子發射光譜儀檢測. / With reference to IEC 62321-4: 2013 and performed by ICP-AES.	2	n.d.
六價鉻 / Hexavalent Chromium Cr(VI)	mg/kg	參考IEC 62321: 2008方法, 以UV-VIS檢測. / With reference to IEC 62321: 2008 and performed by UV-VIS.	2	n.d.
銻 / Antimony (Sb)	mg/kg	參考US EPA 3052方法, 以感應耦合電漿原子發射光譜儀檢測. / With reference to US EPA Method 3052. Analysis was performed by ICP-AES.	2	n.d.

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測試項目 (Test Items)	單位 (Unit)	測試方法 (Method)	方法偵測 極限值 (MDL)	結果 (Result)
				No.1
鄰苯二甲酸甲苯基丁酯 / BBP (Benzyl butyl phthalate) (CAS No.: 85-68-7)	%	參考EN 14372, 以氣相層析/質譜儀檢測之。 / With reference to EN 14372. Analysis was performed by GC/MS.	0.003	n.d.
鄰苯二甲酸二(2-乙基己基)酯 / DEHP (Di-(2-ethylhexyl) phthalate) (CAS No.: 117-81-7)	%	參考EN 14372, 以氣相層析/質譜儀檢測之。 / With reference to EN 14372. Analysis was performed by GC/MS.	0.003	n.d.
鄰苯二甲酸二異癸酯 / DIDP (Di- isodecyl phthalate) (CAS No.: 26761-40-0; 68515-49-1)	%	參考EN 14372, 以氣相層析/質譜儀檢測之。 / With reference to EN 14372. Analysis was performed by GC/MS.	0.01	n.d.
鄰苯二甲酸二異壬酯 / DINP (Di- isononyl phthalate) (CAS No.: 28553-12-0; 68515-48-0)	%	參考EN 14372, 以氣相層析/質譜儀檢測之。 / With reference to EN 14372. Analysis was performed by GC/MS.	0.01	n.d.
鄰苯二甲酸二正辛酯 / DNOP (Di-n- octyl phthalate) (CAS No.: 117- 84-0)	%	參考EN 14372, 以氣相層析/質譜儀檢測之。 / With reference to EN 14372. Analysis was performed by GC/MS.	0.003	n.d.
鄰苯二甲酸二丁酯 / DBP (Dibutyl phthalate) (CAS No.: 84-74-2)	%	參考EN 14372, 以氣相層析/質譜儀檢測之。 / With reference to EN 14372. Analysis was performed by GC/MS.	0.003	n.d.
鄰苯二甲酸二異丁酯 / DIEP (Di- isobutyl phthalate) (CAS No.: 84- 69-5)	%	參考EN 14372, 以氣相層析/質譜儀檢測之。 / With reference to EN 14372. Analysis was performed by GC/MS.	0.003	n.d.

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測試項目 (Test Items)	單位 (Unit)	測試方法 (Method)	方法偵測 極限值 (MDL)	結果 (Result)
				No.1
六溴環十二烷及所有主要被辨別出的異構物 / Hexabromocyclododecane (HBCDD) and all major diastereoisomers identified ( $\alpha$ -HBCDD, $\beta$ -HBCDD, $\gamma$ -HBCDD) (CAS No.: 25637-99-4 and 3194-55-6 (134237-51-7, 134237-50-6, 134237-52-8))	mg/kg	參考IEC 62321: 2008方法, 以氣相層析/質譜儀檢測. / With reference to IEC 62321: 2008 method. Analysis was performed by GC/MS.	5	n.d.
多溴聯苯總和 / Sum of PBBs	mg/kg	參考IEC 62321: 2008方法, 以氣相層析/質譜儀檢測. / With reference to IEC 62321: 2008 and performed by GC/MS.	-	n.d.
一溴聯苯 / Monobromobiphenyl	mg/kg		5	n.d.
二溴聯苯 / Dibromobiphenyl	mg/kg		5	n.d.
三溴聯苯 / Tribromobiphenyl	mg/kg		5	n.d.
四溴聯苯 / Tetrabromobiphenyl	mg/kg		5	n.d.
五溴聯苯 / Pentabromobiphenyl	mg/kg		5	n.d.
六溴聯苯 / Hexabromobiphenyl	mg/kg		5	n.d.
七溴聯苯 / Heptabromobiphenyl	mg/kg		5	n.d.
八溴聯苯 / Octabromobiphenyl	mg/kg		5	n.d.
九溴聯苯 / Nonabromobiphenyl	mg/kg		5	n.d.
十溴聯苯 / Decabromobiphenyl	mg/kg	5	n.d.	

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測試項目 (Test Items)	單位 (Unit)	測試方法 (Method)	方法偵測 極限值 (MDL)	結果 (Result)
				No.1
多溴聯苯醚總和 / Sum of PBDEs	mg/kg	參考IEC 62321: 2008方法, 以氣相層析/質譜儀檢測. / With reference to IEC 62321: 2008 and performed by GC/MS.	-	n.d.
一溴聯苯醚 / Monobromodiphenyl ether	mg/kg		5	n.d.
二溴聯苯醚 / Dibromodiphenyl ether	mg/kg		5	n.d.
三溴聯苯醚 / Tribromodiphenyl ether	mg/kg		5	n.d.
四溴聯苯醚 / Tetrabromodiphenyl ether	mg/kg		5	n.d.
五溴聯苯醚 / Pentabromodiphenyl ether	mg/kg		5	n.d.
六溴聯苯醚 / Hexabromodiphenyl ether	mg/kg		5	n.d.
七溴聯苯醚 / Heptabromodiphenyl ether	mg/kg		5	n.d.
八溴聯苯醚 / Octabromodiphenyl ether	mg/kg		5	n.d.
九溴聯苯醚 / Nonabromodiphenyl ether	mg/kg		5	n.d.
十溴聯苯醚 / Decabromodiphenyl ether	mg/kg	5	n.d.	
鹵素 / Halogen				
鹵素(氟) / Halogen-Fluorine (F) (CAS No.: 14762-94-8)	mg/kg	參考BS EN 14582:2007, 以離子層析儀分析. / With reference to BS EN 14582:2007. Analysis was performed by IC.	50	n.d.
鹵素(氯) / Halogen-Chlorine (Cl) (CAS No.: 22537-15-1)	mg/kg		50	n.d.
鹵素(溴) / Halogen-Bromine (Br) (CAS No.: 10097-32-2)	mg/kg		50	n.d.
鹵素(碘) / Halogen-Iodine (I) (CAS No.: 14362-44-8)	mg/kg		50	n.d.

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### 備註(Note) :

1. mg/kg = ppm ; 0.1wt% = 1000ppm
2. n.d. = Not Detected (未檢出)
3. MDL = Method Detection Limit (方法偵測極限值)
4. "-" = Not Regulated (無規格值)
5. 樣品的測試是基於申請人要求混合測試，報告中的混合測試結果不代表其中個別單一材質的含量。(The samples was/were analyzed on behalf of the applicant as mixing sample in one testing. The above results was/were only given as the informality value.)

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# 測試報告 Test Report

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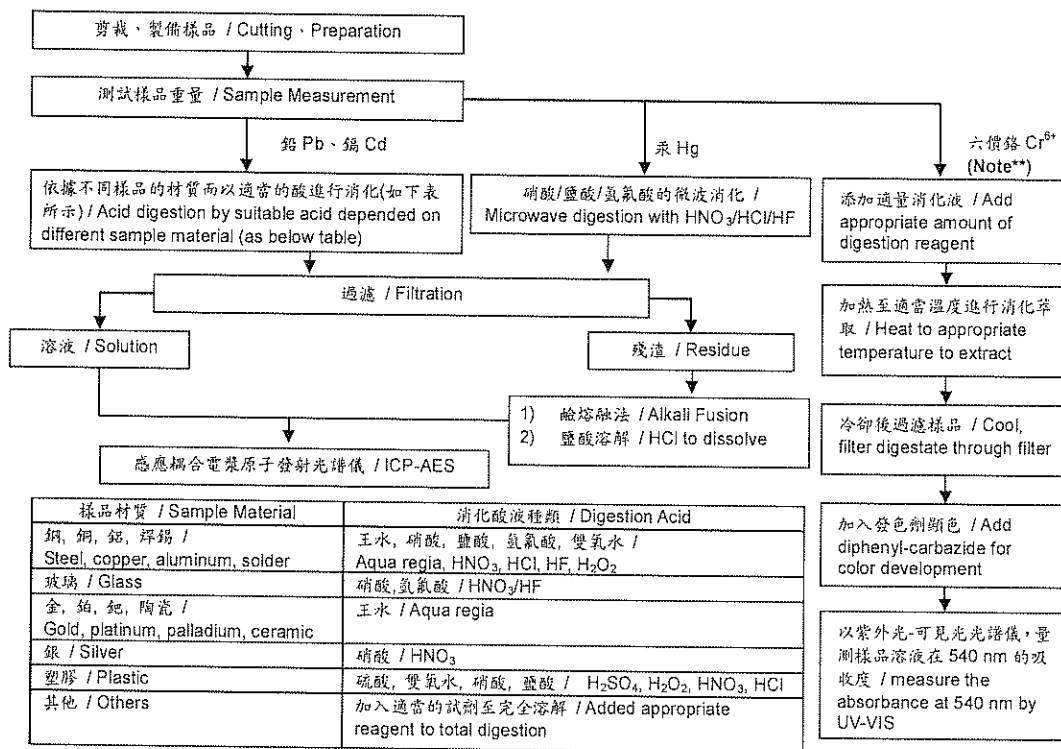
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- 1) 根據以下的流程圖之條件, 樣品已完全溶解。(六價鉻測試方法除外) / These samples were dissolved totally by pre-conditioning method according to below flow chart. (Cr<sup>6+</sup> test method excluded)
- 2) 測試人員: 楊登偉 / Name of the person who made measurement: Climbgreat Yang
- 3) 測試負責人: 張啓興 / Name of the person in charge of measurement: Troy Chang



### Note\*\* (For IEC 62321)

- (1) 針對非金屬材料加入鹼性消化液, 加熱至 90~95℃ 萃取。 / For non-metallic material, add alkaline digestion reagent and heat to 90~95 °C.
- (2) 針對金屬材料加入純水, 加熱至沸騰萃取。 / For metallic material, add pure water and heat to boiling.

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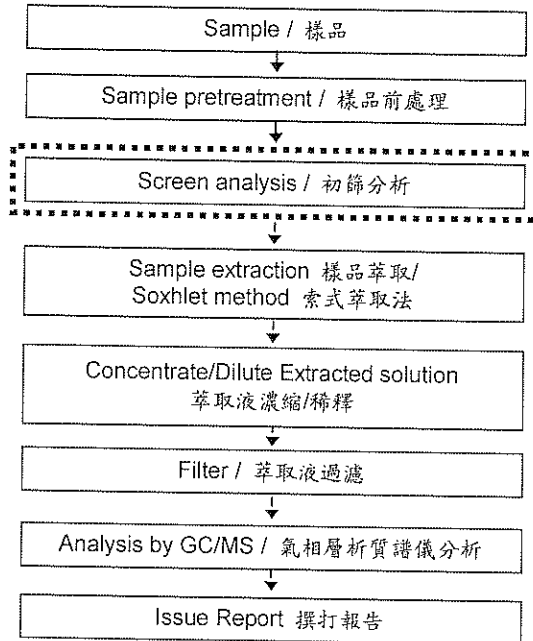
### 多溴聯苯/多溴聯苯醚分析流程圖 / PBB/PBDE analytical FLOW CHART

- 測試人員：翁賜彬 / Name of the person who made measurement: Roman Wong
- 測試負責人：張啓興 / Name of the person in charge of measurement: Troy Chang

初次測試程序 / First testing process —————>

選擇性篩檢程序 / Optional screen process .....>

確認程序 / Confirmation process - - ->



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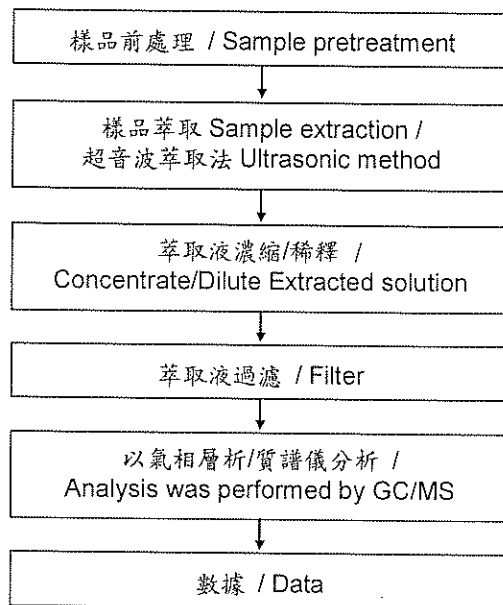
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## 六溴環十二烷分析流程圖 / HBCDD analytical flow chart

- 測試人員：翁賜彬 / Name of the person who made measurement: Roman Wong
- 測試負責人：張啓興 / Name of the person in charge of measurement: Troy Chang



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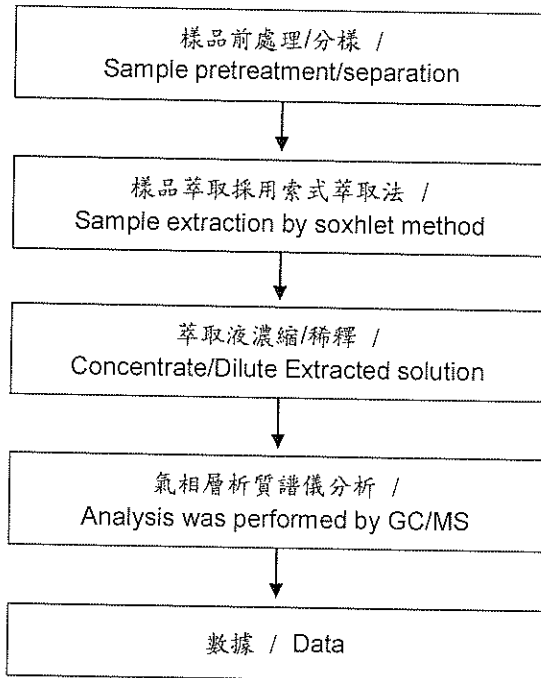
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### 可塑劑分析流程圖 / Analytical flow chart of phthalate content

- 測試人員：翁賜彬 / Name of the person who made measurement: Roman Wong
- 測試負責人：張啓興 / Name of the person in charge of measurement: Troy Chang



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# 測試報告

## Test Report

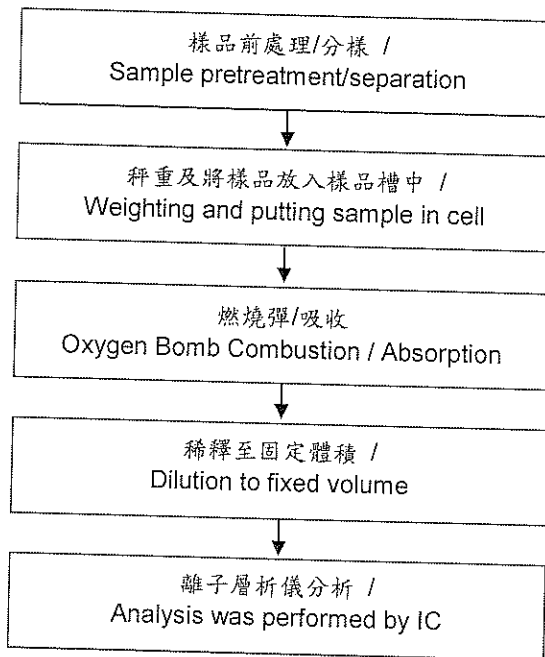
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### 鹵素分析流程圖 / Analytical flow chart of halogen content

- 測試人員：陳恩臻 / Name of the person who made measurement: Rita Chen
- 測試負責人：張啓興 / Name of the person in charge of measurement: Troy Chang



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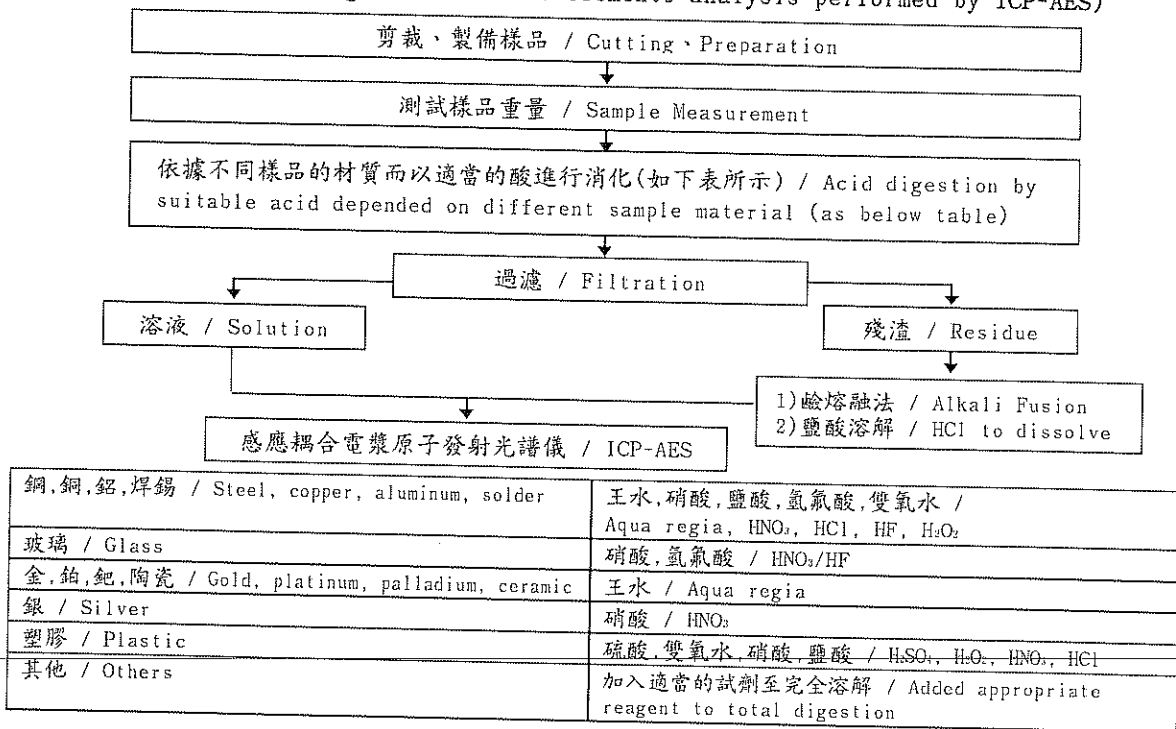


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- 1) 根據以下的流程圖之條件，樣品已完全溶解。 / These samples were dissolved totally by pre-conditioning method according to below flow chart.
- 2) 測試人員：楊登偉 / Name of the person who made measurement: Climbgreat Yang
- 3) 測試負責人：張啓興 / Name of the person in charge of measurement: Troy Chang

### 元素以 ICP-AES 分析的消化流程圖

(Flow Chart of digestion for the elements analysis performed by ICP-AES)



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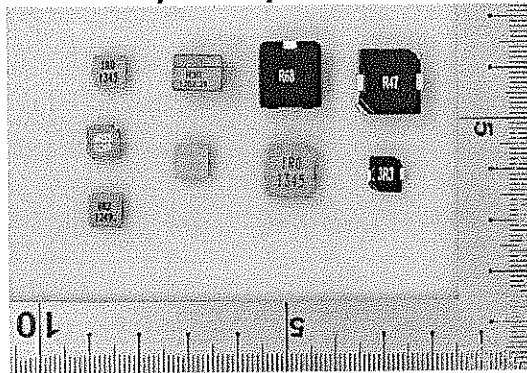
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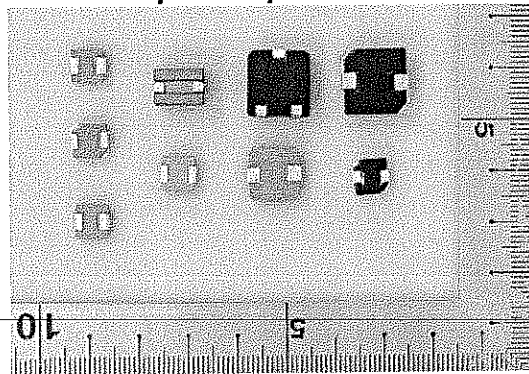
\* 照片中如有箭頭標示，則表示為實際檢測之樣品/部位。\*

(The tested sample / part is marked by an arrow if it's shown on the photo.)

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\*\* 報告結尾 (End of Report) \*\*

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